

MOSFET – Power, N-Channel, SUPERFET[®] III, Easy Drive 650 V, 260 mΩ, 12 A

NVD260N65S3

Features

- Ultra Low Gate Charge & Low Effective Output Capacitance
- Lower FOM (R_{DS(on) max.} x Q_{g typ.} & R_{DS(on) max.} x E_{OSS})
- 100% Avalanche Tested
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	650	٧
Gate-to-Source Voltage - DC	V _{GSS}	±30	٧
Gate-to-Source Voltage - AC (f > 1 Hz)	V _{GSS}	±30	٧
Drain Current – Continuous (T _C = 25°C)	I _D	12	Α
Drain Current – Continuous (T _C = 100°C)	I _D	7.6	Α
Drain Current - Pulsed (Note 3)	I _{DM}	30	Α
Power Dissipation (T _C = 25°C)	P_{D}	90	W
Power Dissipation - Derate Above 25°C	P_{D}	0.72	W/°C
Operating Junction and Storage Temperature Range	T_J , T_{STG}	-55 to +150	°C
Single Pulsed Avalanche Energy (Note 4)	E _{AS}	57	mJ
Repetitive Avalanche Energy (Note 3)	E _{AR}	0.9	mJ
MOSFET dv/dt	dv/dt	100	V/ns
Peak Diode Recovery dv/dt (Note 5)	dv/dt	20	V/ns
Max. Lead Temperature for Soldering Purposes (1/8" from case for 5 s)	TL	300	°C

THERMAL CHARACTERISTICS

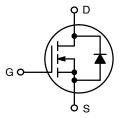
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case, Max. (Notes 1, 2)	$R_{\theta JC}$	1.39	°C/W
Thermal Resistance, Junction-to-Ambient, Max. (Notes 1, 2, 6)	$R_{\theta JA}$	40	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- The entire application environment impacts the thermal resistance values shown.
 They are not constants and are only valid for the particular conditions noted.
- Assembled to an infinite heatsink with perfect heat transfer from the case (assumes 0 K/W thermal interface).
- 3. Repetitive rating: pulse-width limited by maximum junction temperature.
- 4. $I_{AS} = 2.3 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}\text{C}$.
- 5. $I_{SD} \le 6$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le 400$ V, starting $T_J = 25^{\circ}$ C.
- 6. Device on 1 in² pad 2 oz copper pad on 1.5 x 1.5 in. board of FR-4 material.

1

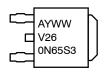
V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	260 m Ω @ 10 V	12 A



POWER MOSFET



MARKING DIAGRAM



A = Assembly Location

Y = Year WW = Work Week

V260N65S3 = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping [†]
NVD260N65S3T4G	DPAK3 (Pb-Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0 \text{ V, } I_D = 1 \text{ mA, } T_J = 25^{\circ}\text{C}$	650			V
Drain-to-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0 V, I _D = 1 mA, T _J = 150°C	700			V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_{J}$	I _D = 1 mA, Referenced to 25°C		660		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 650 V			1	μΑ
		V _{DS} = 520 V, T _C = 125°C		0.77		
Gate-to-Body Leakage Current	I _{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(th)}	$V_{GS} = V_{DS}, I_D = 0.29 \text{ mA}$	2.5		4.5	V
Threshold Temperature Coefficient	$\Delta V_{GS(th)}/\Delta T_J$	$V_{GS} = V_{DS}, I_D = 0.29 \text{ mA}$		-8.9		mV/°C
Static Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 6 A		217	260	mΩ
Forward Transconductance	9FS	V _{DS} = 20 V, I _D = 6 A		7.3		S
DYNAMIC CHARACTERISTICS	<u>'</u>		•	1	I	
Input Capacitance	C _{iss}			1042		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 400 V, f = 1 MHz		22.5		- -
Reverse Transfer Capacitance	C _{rss}			3.8		
Effective Output Capacitance	C _{oss(eff.)}	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		225		pF
Energy Related Output Capacitance	C _{oss(er.)}	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		37.5		pF
Total Gate Charge at 10 V	Q _{G(TOT)}			23.5		nC
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 10 V, V _{DS} = 400 V, I _D = 6 A		3.8		1
Gate-to-Source Gate Charge	Q _{GS}	(Note 7)		6.3		-
Gate-to-Drain "Miller" Charge	Q_{GD}			9.8		1
Equivalent Series Resistance	ESR	f = 1 MHz		8.1		Ω
SWITCHING CHARACTERISTICS			1	1		
Turn-On Delay Time	t _{d(on)}			17.2		ns
Turn-On Rise Time	t _r	V_{GS} = 10 V, V_{DD} = 400 V, I_D = 6 A, R_g = 4.7 Ω		13.9		ns
Turn-Off Delay Time	t _{d(off)}	$I_D = 6 \text{ A}, R_g = 4.7 \Omega$ (Note 7)		48.3		ns
Turn-Off Fall Time	t _f	, ,		8.3		ns
SOURCE-DRAIN DIODE CHARACTER			<u> </u>	<u> </u>	l	
Maximum Continuous Source-to- Drain Diode Forward Current	Is	V _{GS} = 0 V			12	А
Maximum Pulsed Source-to-Drain Diode Forward Current	I _{SM}	V _{GS} = 0 V			30	А
Source-to-Drain Diode Forward Voltage	V _{SD}	V _{GS} = 0 V, I _{SD} = 6 A			1.2	V
Reverse Recovery Time	t _{rr}			232		ns
Charge Time	t _a	$V_{GS} = 0 \text{ V}, dI_F/dt = 100 \text{ A}/\mu\text{s},$		220		1
Discharge Time	t _b	$V_{GS} = 0 \text{ V, dif/di} = 100 \text{ A/}\mu\text{s,}$ $I_{SD} = 6 \text{ A}$		13		1
Reverse Recovery Charge	Q _{rr}			2837		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

7. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

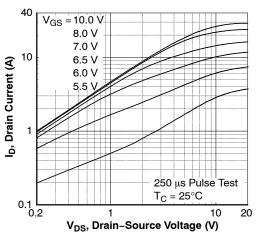


Figure 1. On-Region Characteristics 25°C

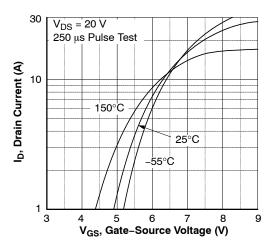


Figure 3. Transfer Characteristics

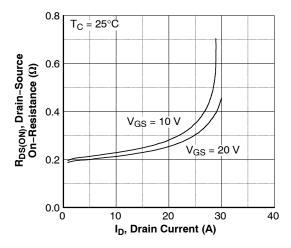


Figure 5. On-Resistance Variation vs. Drain Current and Gate Voltage

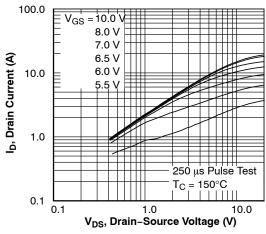


Figure 2. On-Region Characteristics 150°C

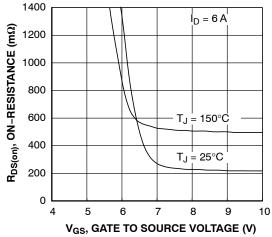


Figure 4. R_{DS(on)} vs. Gate Voltage

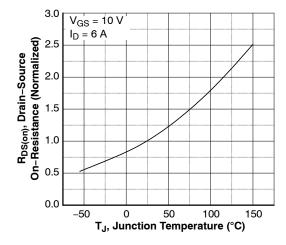


Figure 6. On–Resistance Variation vs. Temperature

TYPICAL CHARACTERISTICS

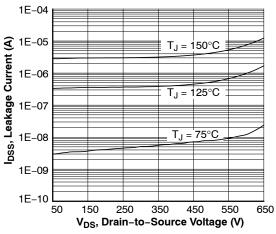


Figure 7. Drain-to-Source Leakage Current vs. Voltage

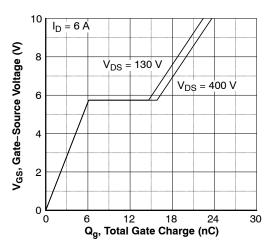


Figure 9. Gate Charge Characteristics

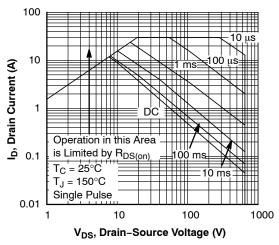


Figure 11. Maximum Safe Operating Area

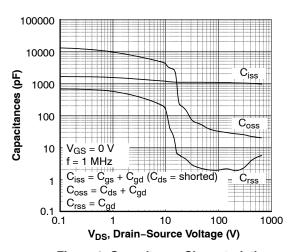


Figure 8. Capacitance Characteristics

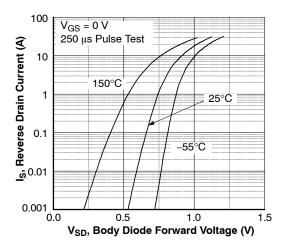


Figure 10. Body Diode Forward Voltage Variation vs. Source Current and Temperature

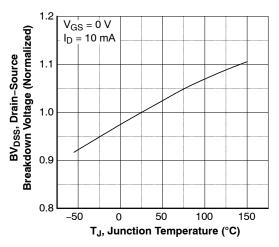


Figure 12. Breakdown Voltage Variation vs. Temperature

TYPICAL CHARACTERISTICS

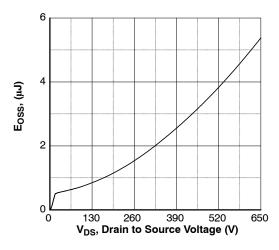


Figure 13. E_{OSS} vs. Drain to Source Voltage

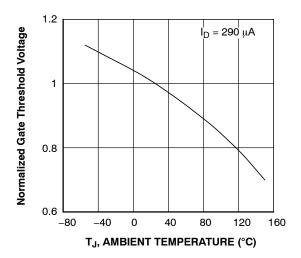


Figure 14. Normalized Gate Threshold Voltage vs. Temperature

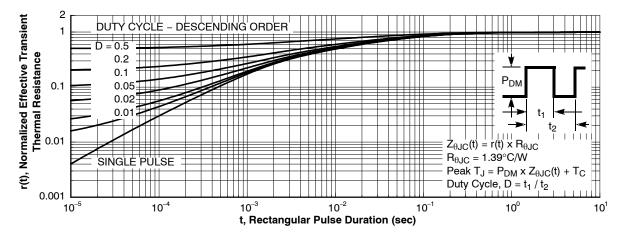


Figure 15. Transient Thermal Response Curve

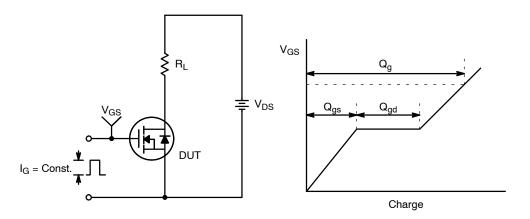


Figure 16. Gate Charge Test Circuit & Waveform

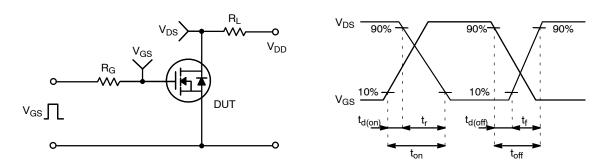


Figure 17. Resistive Switching Test Circuit & Waveforms

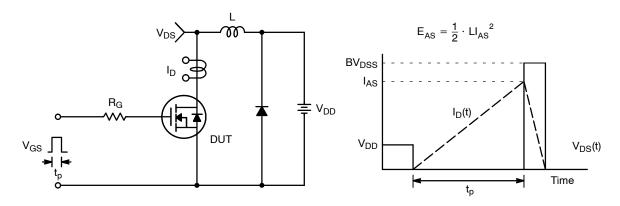


Figure 18. Unclamped Inductive Switching Test Circuit & Waveforms

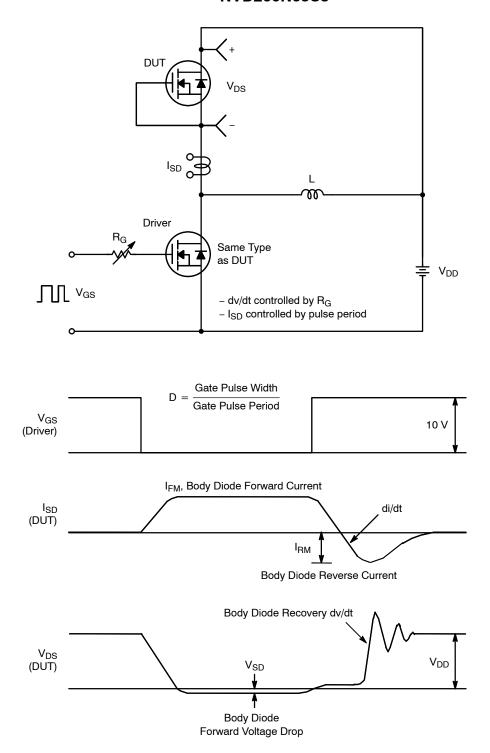


Figure 19. Peak Diode Recovery dv/dt Test Circuit & Waveforms

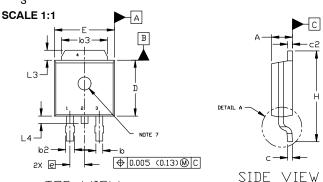
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DPAK (SINGLE GAUGE)

CASE 369C ISSUE G

DATE 31 MAY 2023



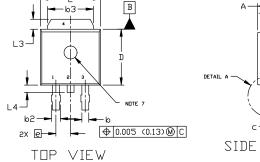


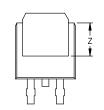
- DIMENSIONING AND TOLERANCING ASME Y14.5M, 1994. CONTROLLING DIMENSION: INCHES
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS 63,
- L3. AND Z. L3, AND Z.

 DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH,
 PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR
 GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
 DIMENSIONS D AND E ARE DETERMINED AT THE
 OUTERMOST EXTREMES OF THE PLASTIC BODY.
 DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
 DETININAL MOLD ESCALUES.

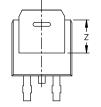
- OPTIONAL MOLD FEATURE.

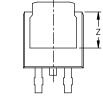
DIM	INCHES		MILLIM	ETERS
ויונע	MIN.	MAX.	MIN.	MAX.
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.028	0.045	0.72	1.14
b3	0.180	0.215	4.57	5.46
C	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090 BSC		2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.114 REF		2.90 REF	
L2	0.020	BSC	0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	







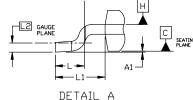




BOTTOM VIEW

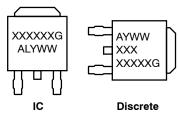
BOTTOM VIEW ALTERNATE CONSTRUCTIONS

5.80 [0.228] 6.20 [0.244] 2.58 3.00 [0.102] [0.118] 1.60 [0.063] 6.17 [0.243]



CW ROTATED 90°

GENERIC MARKING DIAGRAM*



XXXXXX	= Device Code
Α	= Assembly Location
L	= Wafer Lot
Υ	= Year
WW	= Work Week
G	= Pb-Free Package

RECOMMENDED MOUNTING FOOTPRINT* *FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DUWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

STYLE 2:	STYLE 3:	STYLE 4:	STYLE 5:
PIN 1. GATE	PIN 1. ANODE	PIN 1. CATHODE	PIN 1. GATE
2. DRAIN	2. CATHODE	2. ANODE	2. ANODE
3. SOURCE	3. ANODE	3. GATE	3. CATHODE
4. DRAIN	4. CATHODE	4. ANODE	4. ANODE

STYLE 7: PIN 1. GATE 2. COLLECTOR STYLE 6: STYLE 8: STYLE 9: STYLE 10: PIN 1. CATHODE 2. ANODE 3. CATHODE PIN 1. MT1 2. MT2 PIN 1. N/C 2. CATHODE 3. ANODE PIN 1. ANODE 2. CATHODE 3 FMITTER 3 RESISTOR ADJUST 3 GATE 4. COLLECTOR 4. CATHODE 4. ANODE 4. CATHODE

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

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